



TEST REPORT

REGULATION : **FCC Part 1.1310**
(General Population/Uncontrolled Exposure)

Applicant	Testing Laboratory
JVC KENWOOD Corporation 1-16-2, Hakusan, Midori-ku, Yokohama-shi Kanagawa, 226-8525 Japan Tel.: +81 45 939 6254 Fax.: +81 45 939 6261	Intertek Japan K.K. Kashima Laboratory URL: http://www.japan.intertek-etlsemko.com (Open area test site) 3-2 Sunayama, Kamisu, Ibaraki 314-0255 Japan Tel. +81 479 40 1097 (Anechoic chamber) 298-6 Sada, Kashima, Ibaraki 314-0027 Japan Tel. +81 299 82 8464

Equipment type	VHF DIGITAL TRANSCEIVER
Trademark	KENWOOD
FCC Model(s)	NX-5700-K, NX-5700-F
IC Model(s)	NX-5700-K
Serial No.	27
FCC ID	K44471100
IC CN and UPN	282F-471100
Test Result	Complied
Report Number	14100002JKA-003
Report issue date	November 14, 2014

This report is for the exclusive use of Intertek's Client and is provided pursuant to the agreement between Intertek and its Client. Intertek's responsibility and liability are limited to the terms and conditions of the agreement. Intertek assumes no liability to any party, other than to the Client in accordance with the agreement, for any loss, expense or damage occasioned by the use of this report. Only the Client is authorized to permit copying or distribution of this report and then only in its entirety. Any use of the Intertek name or one of its marks for the sale or advertisement of the tested material, product or service must first be approved in writing by Intertek. The observations and test results in this report are relevant only to the sample tested. This report by itself does not imply that the material, product, or service is or has ever been under an Intertek certification program.

Approved by

Kazuo Gokita

[Manager]

Tested by

Koichi Wagatsuma

[Engineer]

TABLE OF CONTENTS

	Page
SECTION 1. INFORMATION	3
SECTION 2. TEST DATA	4
SECTION 3. TEST CONFIGURATION	8
SECTION 4. MEASUREMENT UNCERTAINTY	9
SECTION 5. LIST OF MEASURING INSTRUMENTS	9

SECTION 1. INFORMATION**APPLICANT**

Company	JVC KENWOOD Corporation
Address	1-16-2, Hakusan, Midori-ku, Yokohama-shi Kanagawa, 226-8525 Japan
Contact Person	Tamaki Shimamura

MANUFACTURER

Company	JVC KENWOOD Corporation
Address	1-16-2, Hakusan, Midori-ku, Yokohama-shi Kanagawa, 226-8525 Japan

EQUIPMENT UNDER TEST

FCC Model(s)	NX-5700-K, NX-5700-F	
IC Model(s)	NX-5700-K	
Serial No.	27	
Frequency range	FCC: 150 to 174 MHz , IC: 138 to 144 MHz and 148 to 174 MHz	
FCC ID	K44471100	
IC CN and UPN	282F-471100	
Maximum Power Rating	50	W
Duty cycle	50	%
Collector Current, A	13.0	amps (Maximum)
Collector Voltage, Vdc	13.6	Vdc
Supply Voltage, Vdc	13.6	Vdc

TEST DATE OF ISSUE AND TEST ENGINEER

Date of Issue	October 14, 2014		
temperature	21	to	23.5 [degree C]
Humidity Variation	58	to	60 [%]
Atmospheric Pressure	100.7	to	100.7 [kPa]
Test Engineer	Koichi Wagatsuma		
Test Location	Kashima Immunity Test Room		
Regulations	FCC Part 1.1310 , RSS-102 Issue4 2010		
Test method/Guide	KDB 447498 D01 General RF Exposure Guidance v05r02		
Test Procedure	RJP-TE103		

Revision Summary

Revised Date	Section	Description of Changes

SECTION 2. TEST DATA

The TX antenna place was inside a semi anechoic chamber at height of 0.8 m from the Ground reference plane to simulate being mounted on a vehicle.

The isotropic probe position was a distance of 0.6 m from the TX antenna and the power density was measured from 0.1 m to 2.0 m (at 0.1 m increments) with the peak value.

The EUT is a PTT radio for mobile application with a peak output power of 50 W.

The 1/4 wave antenna (0 dBd gain) was utilized for testing.

(Model No : QWFT120 / Manufacturer : Laird Technologies)

Measurement Result

TX frequency (MHz)	Output Power W	Measurement distance (m)	Power Density (mW/cm ²)	Limit (mW/cm ²)	Result
138.05	50	0.6	0.121	0.200	PASS
150.05	50	0.6	0.107	0.200	PASS
158.05	50	0.6	0.051	0.200	PASS
162.05	50	0.6	0.043	0.200	PASS
173.95	50	0.6	0.068	0.200	PASS

Power Density = 20 measurements data (0.1m - 2.0m) has been averaged.

Limit : General Population/Uncontrolled Exposure

Measurement data

138.05 MHz

Probe Height (m)	Reading Power Density (mW/cm ²)	Probe Factor	Power Density (mW/cm ²)
0.1	0.039	1.33	0.026
0.2	0.072	1.33	0.048
0.3	0.102	1.33	0.068
0.4	0.148	1.33	0.098
0.5	0.189	1.33	0.126
0.6	0.236	1.33	0.157
0.7	0.271	1.33	0.180
0.8	0.273	1.33	0.181
0.9	0.239	1.33	0.158
1.0	0.196	1.33	0.130
1.1	0.191	1.33	0.127
1.2	0.214	1.33	0.142
1.3	0.241	1.33	0.160
1.4	0.259	1.33	0.172
1.5	0.243	1.33	0.161
1.6	0.210	1.33	0.139
1.7	0.180	1.33	0.119
1.8	0.140	1.33	0.093
1.9	0.110	1.33	0.073
2.0	0.088	1.33	0.058

Power Density = Reading Power Density x Probe Factor x Duty cycle (50%)

150.05 MHz

Probe Height (m)	Reading Power Density (mW/cm ²)	Probe Factor	Power Density (mW/cm ²)
0.1	0.012	1.36	0.008
0.2	0.038	1.36	0.026
0.3	0.066	1.36	0.045
0.4	0.103	1.36	0.070
0.5	0.141	1.36	0.096
0.6	0.170	1.36	0.115
0.7	0.201	1.36	0.137
0.8	0.216	1.36	0.146
0.9	0.208	1.36	0.141
1.0	0.198	1.36	0.134
1.1	0.202	1.36	0.137
1.2	0.224	1.36	0.152
1.3	0.242	1.36	0.164
1.4	0.243	1.36	0.165
1.5	0.227	1.36	0.154
1.6	0.195	1.36	0.132
1.7	0.163	1.36	0.111
1.8	0.128	1.36	0.087
1.9	0.102	1.36	0.069
2.0	0.087	1.36	0.059

Power Density = Reading Power Density x Probe Factor x Duty cycle (50%)

158.05 MHz

Probe Height (m)	Reading Power Density (mW/cm ²)	Probe Factor	Power Density (mW/cm ²)
0.1	0.005	1.38	0.003
0.2	0.020	1.38	0.013
0.3	0.037	1.38	0.026
0.4	0.057	1.38	0.039
0.5	0.070	1.38	0.048
0.6	0.084	1.38	0.058
0.7	0.097	1.38	0.067
0.8	0.108	1.38	0.074
0.9	0.108	1.38	0.074
1.0	0.106	1.38	0.073
1.1	0.106	1.38	0.073
1.2	0.111	1.38	0.076
1.3	0.114	1.38	0.078
1.4	0.107	1.38	0.074
1.5	0.094	1.38	0.064
1.6	0.080	1.38	0.055
1.7	0.064	1.38	0.044
1.8	0.049	1.38	0.034
1.9	0.037	1.38	0.025
2.0	0.028	1.38	0.019

Power Density = Reading Power Density x Probe Factor x Duty cycle (50%)

162.05 MHz

Probe Height (m)	Reading Power Density (mW/cm ²)	Probe Factor	Power Density (mW/cm ²)
0.1	0.004	1.39	0.003
0.2	0.016	1.39	0.011
0.3	0.030	1.39	0.021
0.4	0.046	1.39	0.032
0.5	0.057	1.39	0.040
0.6	0.067	1.39	0.046
0.7	0.080	1.39	0.055
0.8	0.090	1.39	0.062
0.9	0.089	1.39	0.061
1.0	0.090	1.39	0.062
1.1	0.092	1.39	0.064
1.2	0.094	1.39	0.065
1.3	0.096	1.39	0.066
1.4	0.091	1.39	0.063
1.5	0.083	1.39	0.058
1.6	0.070	1.39	0.048
1.7	0.056	1.39	0.039
1.8	0.043	1.39	0.030
1.9	0.032	1.39	0.022
2.0	0.024	1.39	0.017

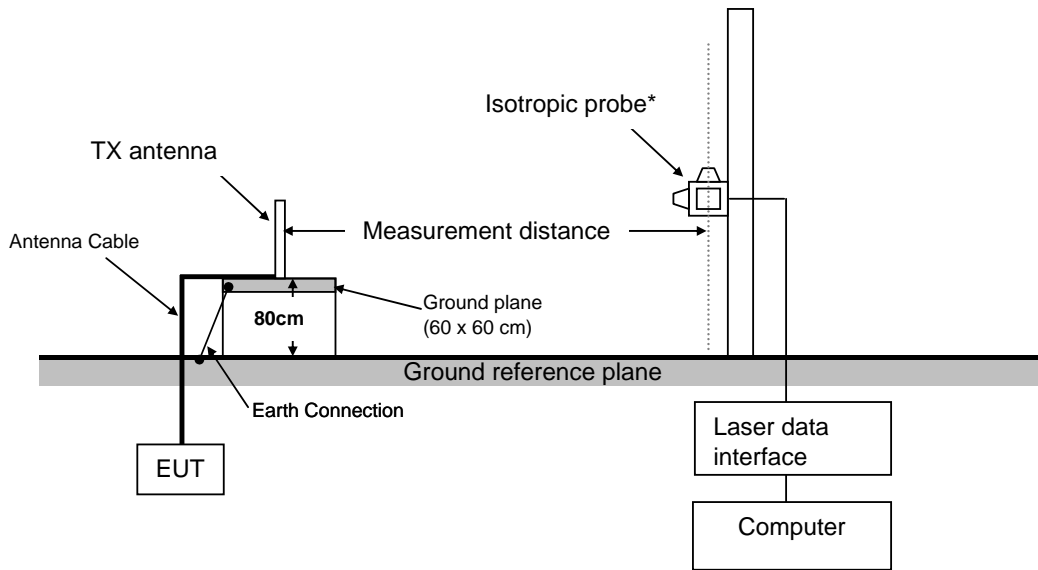
Power Density = Reading Power Density x Probe Factor x Duty cycle (50%)

173.95 MHz

Probe Height (m)	Reading Power Density (mW/cm ²)	Probe Factor	Power Density (mW/cm ²)
0.1	0.013	1.42	0.009
0.2	0.040	1.42	0.028
0.3	0.065	1.42	0.046
0.4	0.089	1.42	0.063
0.5	0.106	1.42	0.075
0.6	0.119	1.42	0.084
0.7	0.129	1.42	0.092
0.8	0.145	1.42	0.102
0.9	0.156	1.42	0.110
1.0	0.155	1.42	0.110
1.1	0.153	1.42	0.108
1.2	0.149	1.42	0.105
1.3	0.141	1.42	0.100
1.4	0.123	1.42	0.087
1.5	0.105	1.42	0.074
1.6	0.082	1.42	0.058
1.7	0.062	1.42	0.044
1.8	0.044	1.42	0.031
1.9	0.032	1.42	0.023
2.0	0.023	1.42	0.016

Power Density = Reading Power Density x Probe Factor x Duty cycle (50%)

SECTION 3. TEST CONFIGURATION



* : The Isotropic probe position was Vertical orientation from the Ground reference plane from 0.1m to 2m (10cm increments) .

Setup Photos



SECTION 4. MEASUREMENT UNCERTAINTY

30 MHz – 1000 MHz	17.7 % (k=2)
-------------------	--------------

SECTION 5. LIST OF MEASURING INSTRUMENTS

Instrument	Model No.	Serial No.	Manufacturer	Cal Date	Cal Due Date
Isotropic probe	HI-6105	00130667	ETS Lindgren	2014/4/2	2015/4/30
Laser data interface	HI 6113	00130903	ETS Lindgren	N/A	N/A
Testing software	ProbeView™ Laser	Version 2.0.8	ETS Lindgren	N/A	N/A